

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/990,558	CHOI ET AL.	
Examiner	Art Unit	
John L. Shew	2616	

SEARCHED				
Class	Subclass	Date	Examiner	
370	320,329	7/28/2006	JS	
	331	_		
	332,335			
	336,337			
	338	8/1/2006	JS	
	342,348	7/28/2006		
	349,437			
	441			
455	432.1	7/28/2006	JS	
	432.3			
	433,436			
	439,442			
	450,452			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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